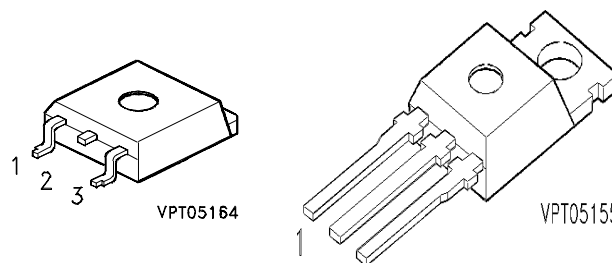


**SIPMOS® Power Transistor**

- N-Channel
- Enhancement mode
- Avalanche rated
- dv/dt rated
- 175°C operating temperature



Pin 1	Pin 2	Pin 3
G	D	S

Type	V <sub>DS</sub>	I <sub>D</sub>	R <sub>DS(on)</sub>	@ V <sub>GS</sub>	Package	Ordering Code
SPP80N03	30 V	80 A	0.006 Ω	V <sub>GS</sub> = 10 V	P-TO220-3-1	Q67040-S4734-A2
SPB80N03					P-TO263-3-2	Q67040-S4734-A3

**Maximum Ratings, at T<sub>j</sub> = 25 °C, unless otherwise specified**

Parameter	Symbol	Value	Unit
Continuous drain current T <sub>C</sub> = 25 °C, <sup>1)</sup> T <sub>C</sub> = 100 °C	I <sub>D</sub>	80 80	A
Pulsed drain current T <sub>C</sub> = 25 °C	I <sub>D puls</sub>	320	
Avalanche energy, single pulse I <sub>D</sub> = 80 A, V <sub>DD</sub> = 25 V, R <sub>GS</sub> = 25 Ω	E <sub>AS</sub>	700	mJ
Avalanche current, periodic limited by T <sub>jmax</sub>	I <sub>AR</sub>	80	A
Avalanche energy, periodic limited by T <sub>j(max)</sub>	E <sub>AR</sub>	30	mJ
Reverse diode dv/dt I <sub>S</sub> = 80 A, V <sub>DS</sub> = 24 V, di/dt = 200 A/μs, T <sub>jmax</sub> = 175 °C	dv/dt	6	kV/μs
Gate source voltage	V <sub>GS</sub>	±20	V
Power dissipation T <sub>C</sub> = 25 °C	P <sub>tot</sub>	300	W
Operating temperature	T <sub>j</sub>	-55 ... +175	°C
Storage temperature	T <sub>stg</sub>	-55 ... +175	
IEC climatic category; DIN IEC 68-1		55/175/56	

<sup>1</sup>current limited by bond wire

**Electrical Characteristics**

Parameter at $T_j = 25\text{ °C}$ , unless otherwise specified	Symbol	Values			Unit
		min.	typ.	max.	

**Thermal Characteristics**

Thermal resistance, junction - case	$R_{thJC}$	-	-	0.5	K/W
Thermal resistance, junction - ambient	$R_{thJA}$	-	62	-	
SMD version, device on PCB: @ min. footprint @ 6 cm <sup>2</sup> cooling area <sup>1)</sup>	$R_{thJA}$	-	tbd	-	

**Static Characteristics**

Drain- source breakdown voltage $V_{GS} = 0\text{ V}$ , $I_D = 0.25\text{ mA}$ , $T_j = 25\text{ °C}$	$V_{(BR)DSS}$	30	-	-	V
Gate threshold voltage, $V_{GS} = V_{DS}$ $I_D = 240\text{ }\mu\text{A}$ , $T_j = 25\text{ °C}$	$V_{GS(th)}$	2.1	3	4	
Zero gate voltage drain current $V_{DS} = 30\text{ V}$ , $V_{GS} = 0\text{ V}$ , $T_j = 25\text{ °C}$ $V_{DS} = 30\text{ V}$ , $V_{GS} = 0\text{ V}$ , $T_j = 150\text{ °C}$	$I_{DSS}$	-	0.1	1	$\mu\text{A}$
Gate-source leakage current $V_{GS} = 20\text{ V}$ , $V_{DS} = 0\text{ V}$	$I_{GSS}$	-	10	100	
Drain-Source on-state resistance $V_{GS} = 10\text{ V}$ , $I_D = 80\text{ A}$	$R_{DS(on)}$	-	0.0038	0.006	$\Omega$

<sup>1</sup> Device on 50mm\*50mm\*1.5mm epoxy PCB FR4 with 6 cm<sup>2</sup> (one layer, 70 $\mu\text{m}$  thick) copper area for drain connection. PCB is vertical without blown air.

**Electrical Characteristics**

Parameter at $T_j = 25\text{ }^\circ\text{C}$ , unless otherwise specified	Symbol	Values			Unit
		min.	typ.	max.	

**Dynamic Characteristics**

Transconductance $V_{DS} \geq 2 \cdot I_D \cdot R_{DS(on)max}$ , $I_D = 80\text{ A}$	$g_{fs}$	30	93	-	S
Input capacitance $V_{GS} = 0\text{ V}$ , $V_{DS} = 25\text{ V}$ , $f = 1\text{ MHz}$	$C_{iss}$	-	3970	5000	pF
Output capacitance $V_{GS} = 0\text{ V}$ , $V_{DS} = 25\text{ V}$ , $f = 1\text{ MHz}$	$C_{oss}$	-	1920	2500	
Reverse transfer capacitance $V_{GS} = 0\text{ V}$ , $V_{DS} = 25\text{ V}$ , $f = 1\text{ MHz}$	$C_{rss}$	-	775	1000	
Turn-on delay time $V_{DD} = 15\text{ V}$ , $V_{GS} = 10\text{ V}$ , $I_D = 80\text{ A}$ , $R_G = 2.5\text{ }\Omega$	$t_{d(on)}$	-	22	33	ns
Rise time $V_{DD} = 15\text{ V}$ , $V_{GS} = 10\text{ V}$ , $I_D = 80\text{ A}$ , $R_G = 2.5\text{ }\Omega$	$t_r$	-	25	38	
Turn-off delay time $V_{DD} = 15\text{ V}$ , $V_{GS} = 10\text{ V}$ , $I_D = 80\text{ A}$ , $R_G = 2.5\text{ }\Omega$	$t_{d(off)}$	-	55	85	
Fall time $V_{DD} = 15\text{ V}$ , $V_{GS} = 10\text{ V}$ , $I_D = 80\text{ A}$ , $R_G = 2.5\text{ }\Omega$	$t_f$	-	40	60	

**Electrical Characteristics**

Parameter at $T_i = 25\text{ °C}$ , unless otherwise specified	Symbol	Values			Unit
		min.	typ.	max.	

**Dynamic Characteristics**

Gate charge at threshold $V_{DD} = 24\text{ V}$ , $I_D \geq 0,1\text{ A}$ , $V_{GS} = 0\text{ to }1\text{ V}$	$Q_{G(th)}$	-	4	6	nC
Gate charge at $V_{GS}=7\text{ V}$ $V_{DD} = 24\text{ V}$ , $I_D = 80\text{ A}$ , $V_{GS} = 0\text{ to }7\text{ V}$	$Q_{g(7)}$	-	90	135	nC
Gate charge total $V_{DD} = 24\text{ V}$ , $I_D = 80\text{ A}$ , $V_{GS} = 0\text{ to }10\text{ V}$	$Q_g$	-	112	175	
Gate plateau voltage $V_{DD} = 24\text{ V}$ , $I_D = 80\text{ A}$	$V_{(plateau)}$	-	4.7	-	V

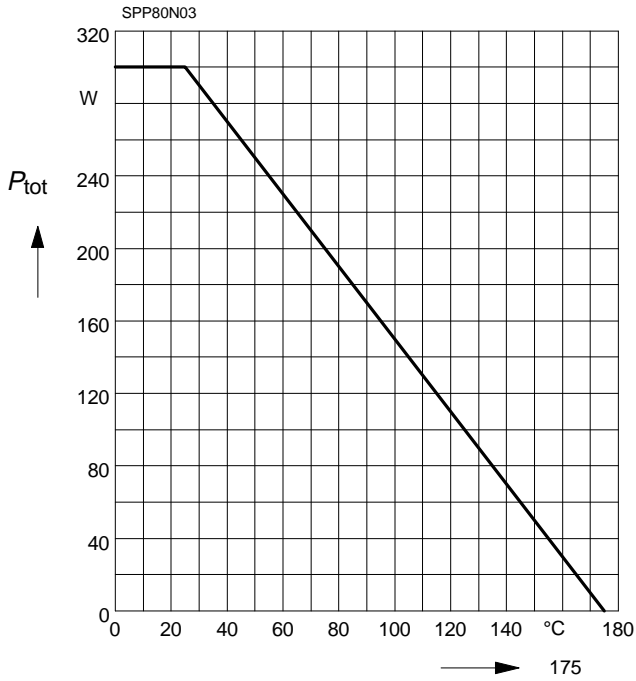
**Reverse Diode**

Inverse diode continuous forward current $T_C = 25\text{ °C}$	$I_S$	-	-	80	A
Inverse diode direct current,pulsed $T_C = 25\text{ °C}$	$I_{SM}$	-	-	320	
Inverse diode forward voltage $V_{GS} = 0\text{ V}$ , $I_F = 160\text{ A}$	$V_{SD}$	-	1.1	1.7	V
Reverse recovery time $V_R = 15\text{ V}$ , $I_F=I_S$ , $di_F/dt = 100\text{ A}/\mu\text{s}$	$t_{rr}$	-	60	90	ns
Reverse recovery charge $V_R = 15\text{ V}$ , $I_F=I_S$ , $di_F/dt = 100\text{ A}/\mu\text{s}$	$Q_{rr}$	-	0.06	0.09	$\mu\text{C}$

**Preliminary data**

**Power Dissipation**

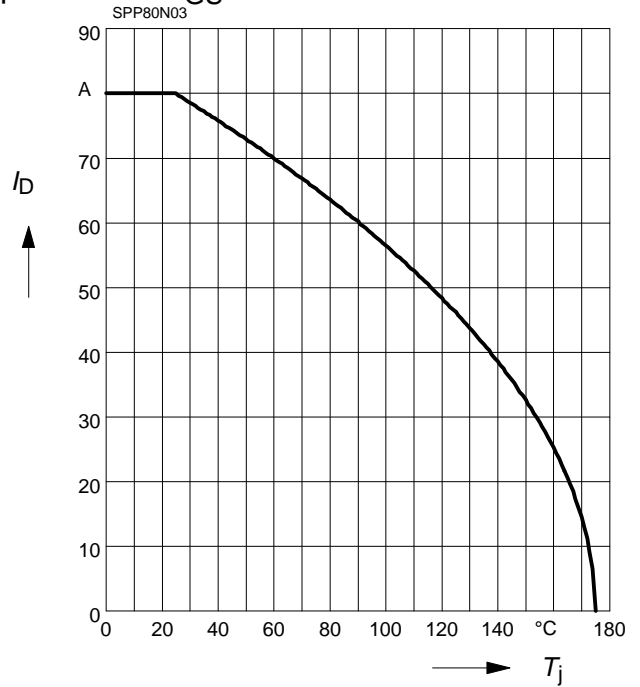
$P_{tot} = f(T_C)$



**Drain current**

$I_D = f(T_C)$

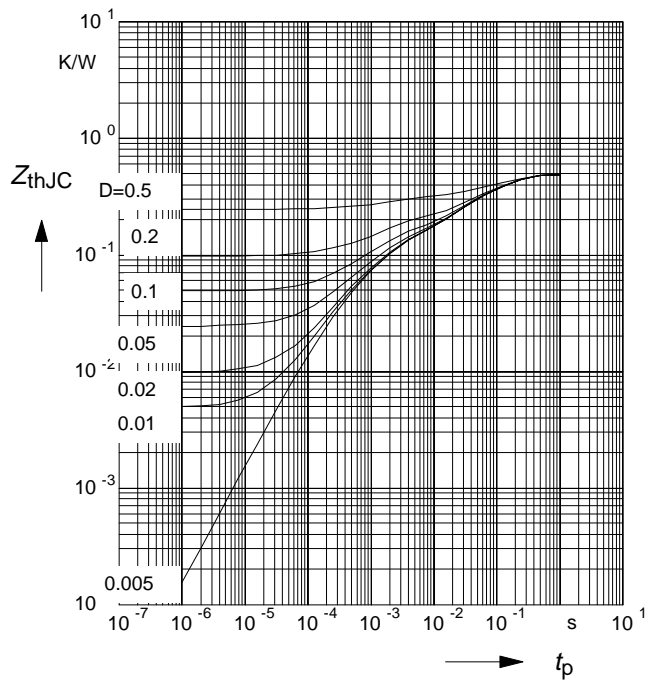
parameter:  $V_{GS} \geq 10\text{ V}$



**Transient thermal impedance**

$Z_{thJC} = f(t_p)$

parameter:  $D = t_p/T$

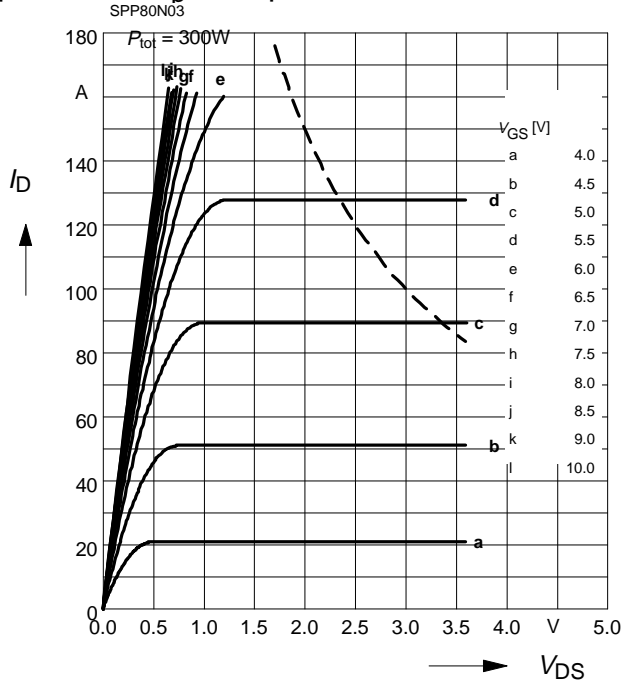


Preliminary data

Typ. output characteristics

$$I_D = f(V_{DS})$$

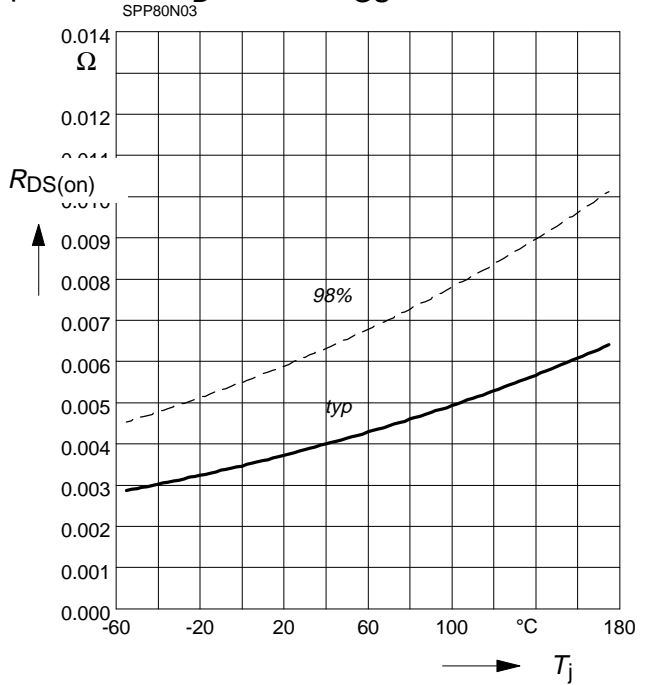
parameter:  $t_D = 80 \mu s$



Drain-source on-resistance

$$R_{DS(on)} = f(T_j)$$

parameter:  $I_D = 80 A, V_{GS} = 10 V$

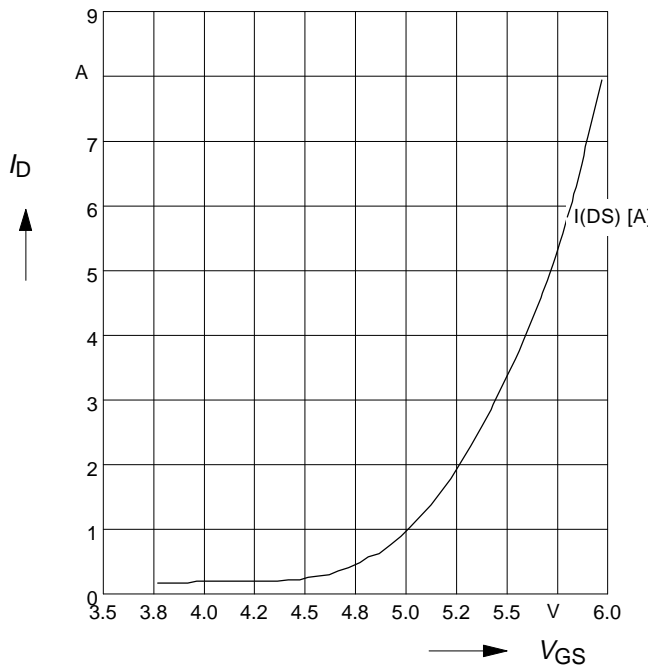


**Preliminary data**

**Typ. transfer characteristics  $I_D = f(V_{GS})$**

parameter:  $t_p = 80 \mu s$

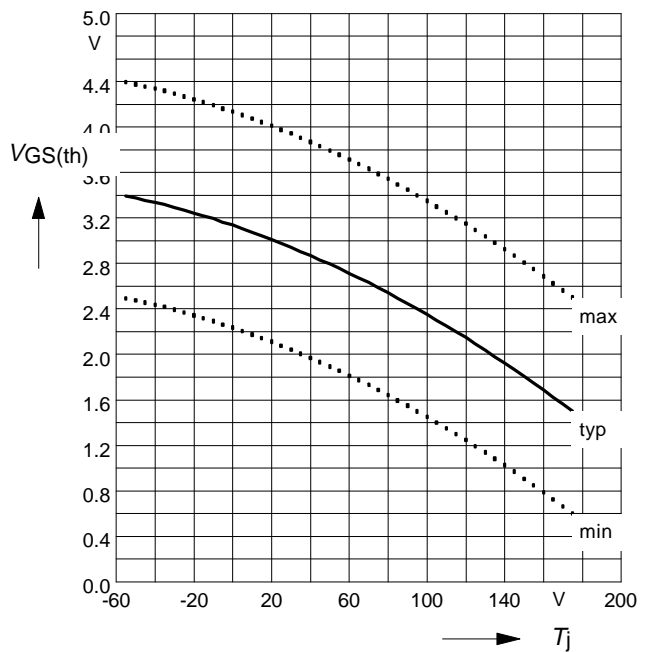
$V_{DS} \geq 2 \times I_D \times R_{DS(on)max}$



**Gate threshold voltage  $V_{GS(th)} = f(T_j)$**

$V_{GS(th)} = f(T_j)$

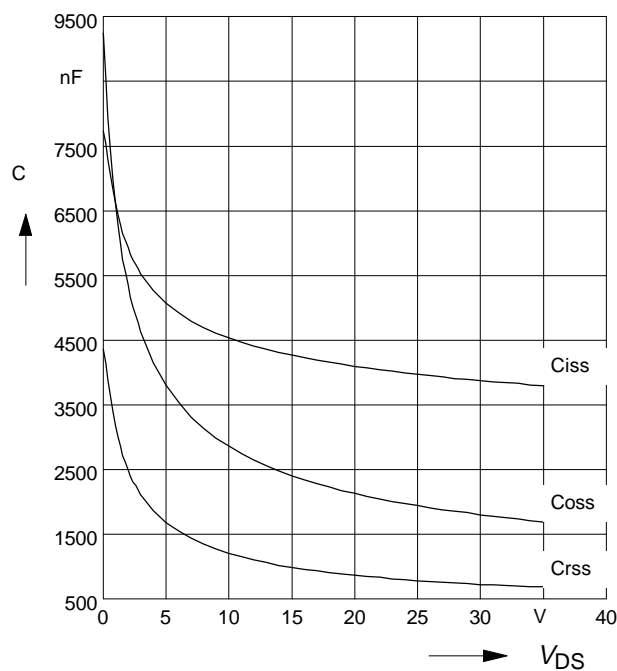
parameter:  $V_{GS} = V_{DS}, I_D = 240 \mu A$



**Typ. capacitances  $C = f(V_{DS})$**

$C = f(V_{DS})$

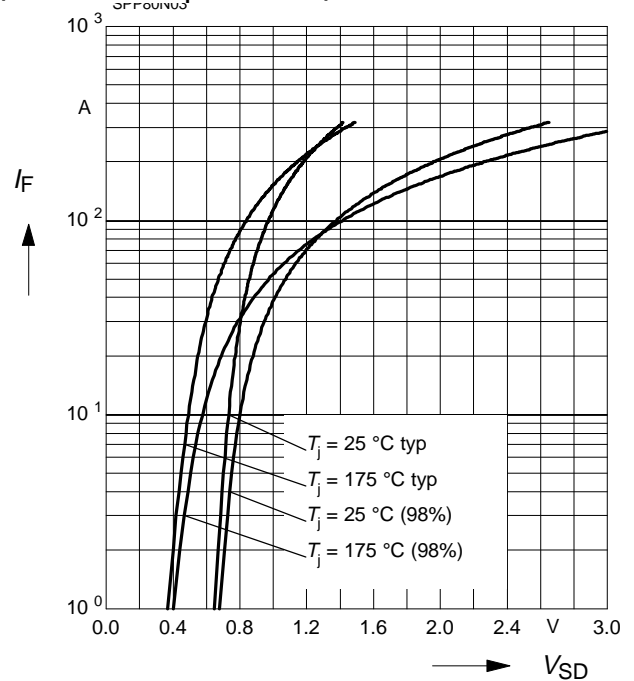
Parameter:  $V_{GS} = 0 V, f = 1 MHz$



**Forward characteristics of reverse diode  $I_F = f(V_{SD})$**

$I_F = f(V_{SD})$

parameter:  $T_j, t_p = 80 \mu s$

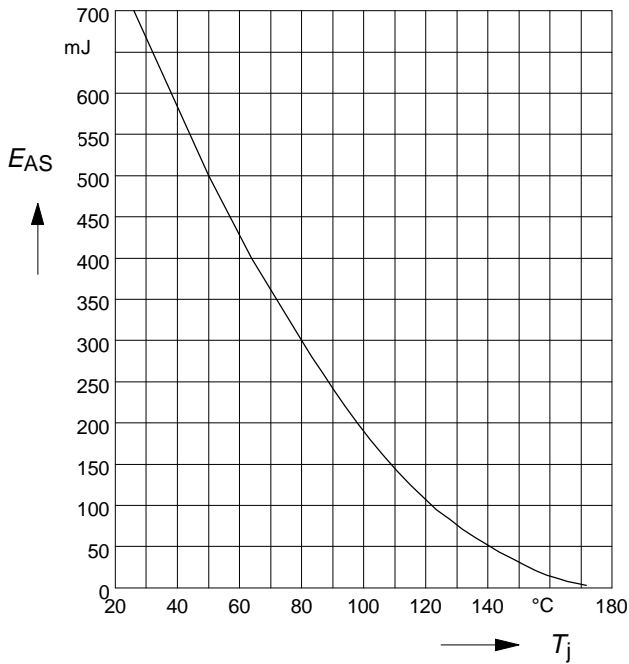


**Preliminary data**

**Avalanche Energy  $E_{AS} = f(T_j)$**

parameter:  $I_D = 80\text{ A}$ ,  $V_{DD} = 25\text{ V}$

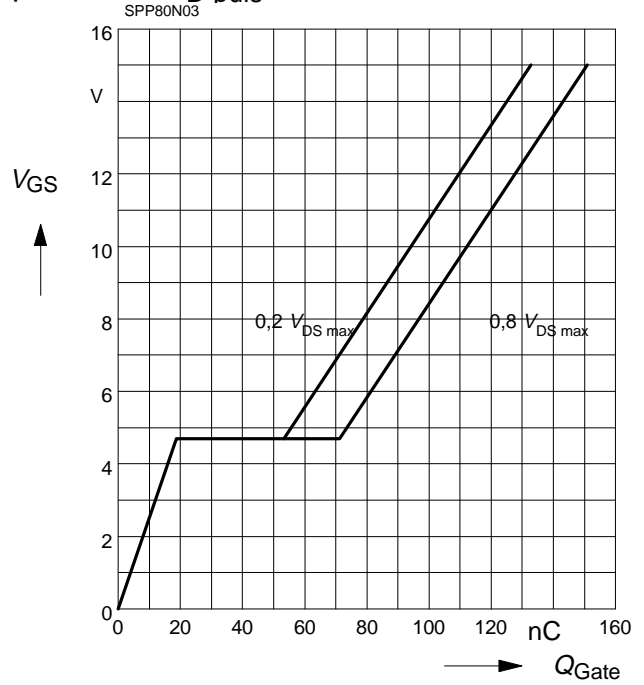
$R_{GS} = 25\ \Omega$



**Typ. gate charge  $V_{GS} = f(Q_{Gate})$**

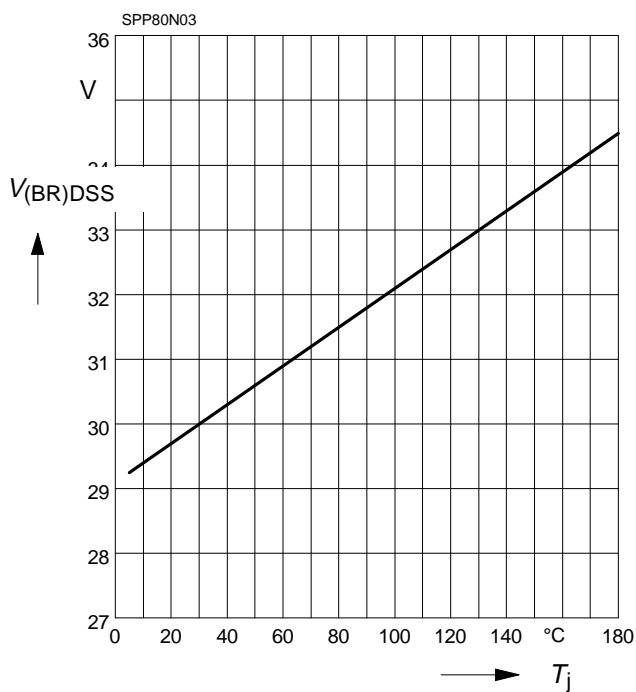
parameter:  $I_{D\text{ puls}} = 80\text{ A}$

parameter:  $I_{D\text{ puls}} = 80\text{ A}$



**Drain-source breakdown voltage  $V_{(BR)DSS} = f(T_j)$**

$V_{(BR)DSS} = f(T_j)$





**Edition 7.97**

**Published by Siemens AG,  
Bereich Halbleiter Vertrieb,  
Werbung, Balanstraße 73,  
81541 München**

© Siemens AG 1997

All Rights Reserved.

**Attention please!**

As far as patents or other rights of third parties are concerned, liability is only assumed for components, not for applications, processes and circuits implemented within components or assemblies.

The information describes a type of component and shall not be considered as warranted characteristics.

Terms of delivery and rights to change design reserved.

For questions on technology, delivery and prices please contact the Semiconductor Group Offices in Germany or the Siemens Companies and Representatives worldwide (see address list).

Due to technical requirements components may contain dangerous substances. For information on the types in question please contact your nearest Siemens Office, Semiconductor Group.

Siemens AG is an approved CECC manufacturer.

**Packing**

Please use the recycling operators known to you. We can also help you - get in touch with your nearest sales office. By agreement we will take packing material back, if it is sorted. You must bear the costs of transport.

For packing material that is returned to us unsorted or which we are not obliged to accept, we shall have to invoice you for any costs incurred.

**Components used in life-support devices or systems must be expressly authorized for such purpose!**

Critical components<sup>1</sup> of the Semiconductor Group of Siemens AG, may only be used in life-support devices or systems<sup>2</sup> with the express written approval of the Semiconductor Group of Siemens AG.

1) A critical component is a component used in a life-support device or system whose failure can reasonably be expected to cause the failure of that life-support device or system, or to affect its safety or effectiveness of that device or system.

2) Life support devices or systems are intended (a) to be implanted in the human body, or (b) to support and/or